Hybrid 8j323 Traveler

April 24, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J323 has die: 000-000 000-000 000-000 000-000 000-000 000-000 000-000 000-000

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j323 classification info. Created 10:00:28 04/24/00

Hybrid 8j323 quality: fair
Chip classification: fair good fair fair good fair good good
Bad channels (chip-channel): 0-127 2-44 3-105 5-71
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-24-43 3-4-126 5-19-71
   5-2-71 5-22-71 5-24-71 5-26-71 5-35-70 5-35-71 5-36-71
Channels at pedestal needed for DCMS: 29.6 30.2 29.6 29.6 31.7 31.7 33.6 32.6
```

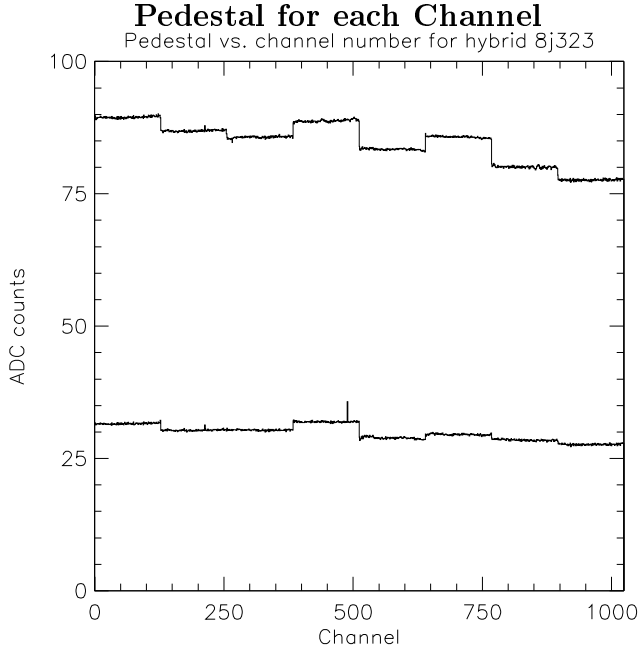
4 Comments

HV tested.

5 Pedestal

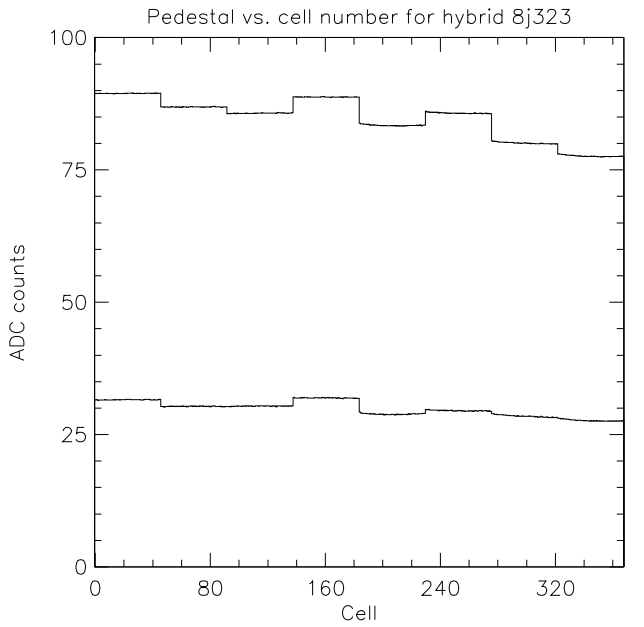
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

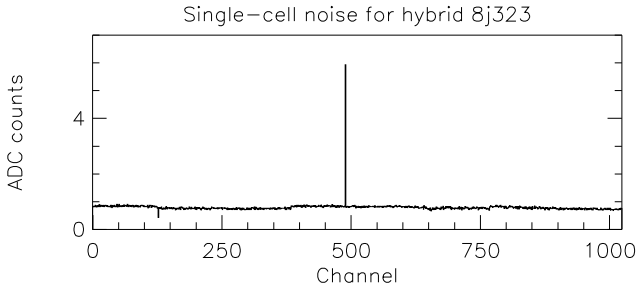
Pedestal vs. Pipeline Cell ID

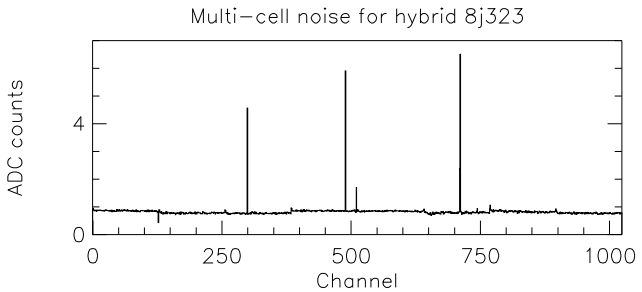


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

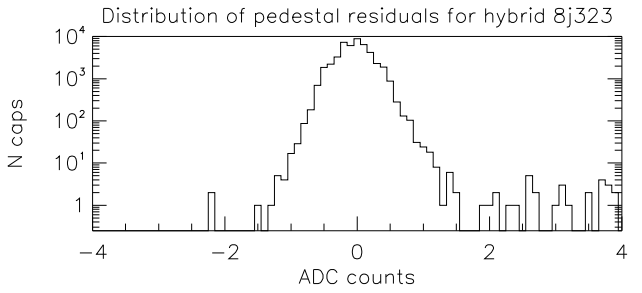
RMS Noise

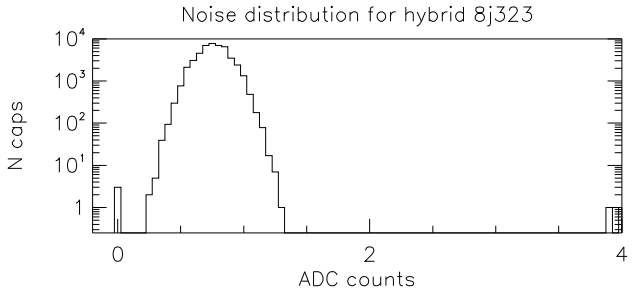




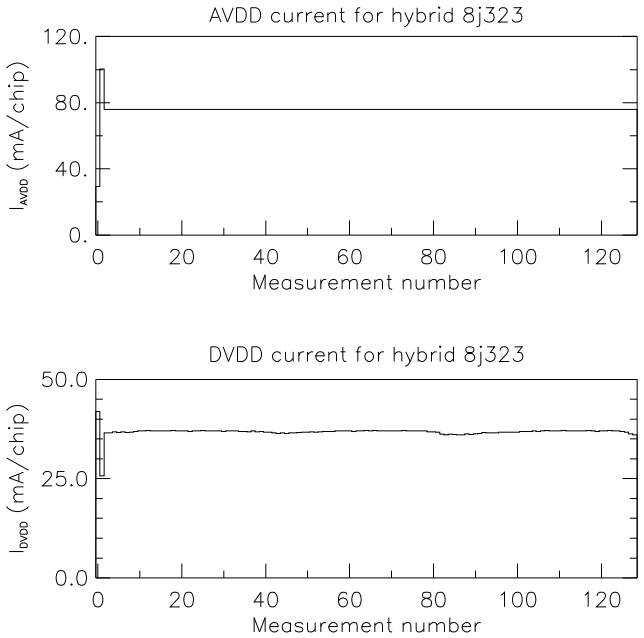
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in